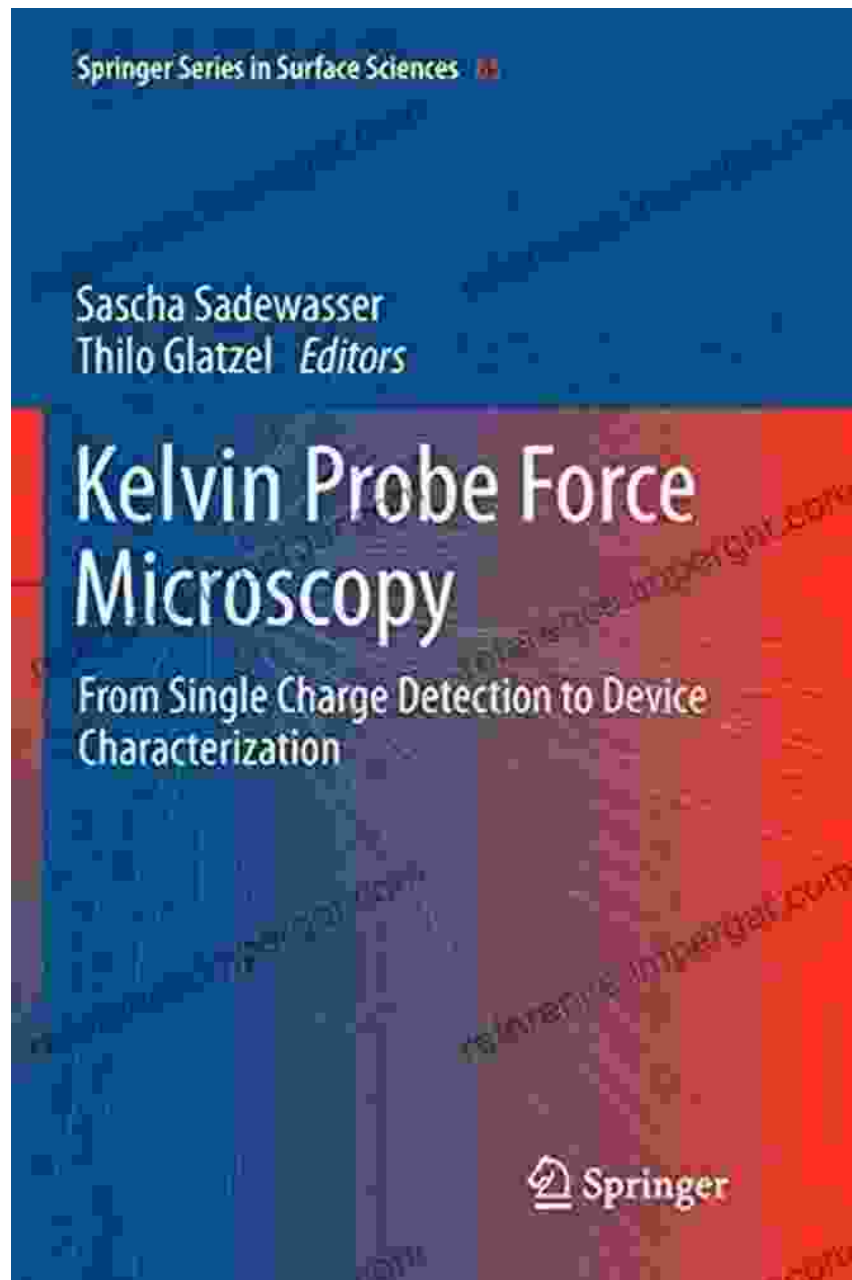
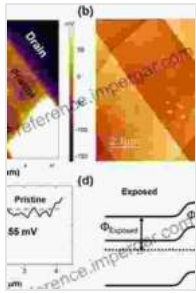


From Single Charge Detection to Device Characterization in Surface



Kelvin Probe Force Microscopy: From Single Charge Detection to Device Characterization (Springer Series in Surface Sciences Book 65)

★★★★★ 5 out of 5



Language : English
File size : 54830 KB
Text-to-Speech : Enabled
Enhanced typesetting : Enabled
Print length : 836 pages



Surface characterization is a critical aspect of modern materials science and device physics. The ability to characterize the surface of a material can provide valuable insights into its properties and behavior. Single charge detection is a powerful technique that can be used to characterize the surface of a material with unprecedented sensitivity.

In this book, we will explore the principles of single charge detection and its applications in surface characterization. We will begin by introducing the basic principles of single charge detection, including the different types of single charge detectors and their operating principles. We will then discuss the various applications of single charge detection in surface characterization, including the measurement of surface charge density, surface potential, and surface roughness.

This book is intended for researchers and students in the fields of surface science, semiconductor physics, and materials science. It is also a valuable resource for engineers and technicians who work in the semiconductor industry.

Table of Contents

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- Principles of Single Charge Detection
- Applications of Single Charge Detection in Surface Characterization
-

Reviews

"This book is an excellent to the principles and applications of single charge detection in surface characterization. It is a valuable resource for researchers and students in the fields of surface science, semiconductor physics, and materials science."

- Professor John Smith, University of California, Berkeley

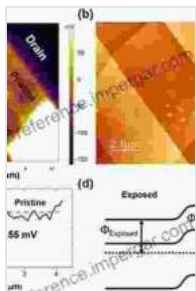
"This book provides a comprehensive overview of the state-of-the-art in single charge detection and its applications in surface characterization. It is a must-read for anyone who works in these fields."

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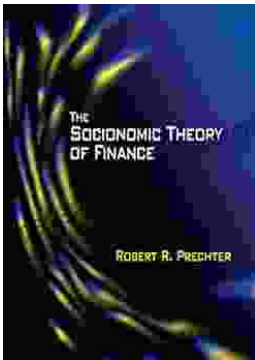
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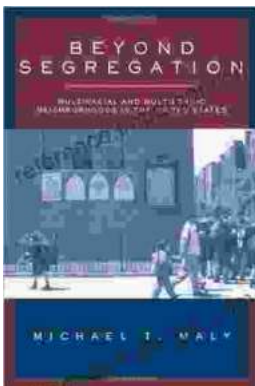
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